

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination FUJIWARA ET AL.	
		Examiner Huy Q Phan	Art Unit 2685	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,565,857 A	10-1996	Lee, Kwang-sil	340/5.42
	B	US-5,991,614 A	11-1999	Oura, Hideto	455/404.1
	C	US-6,625,455 B1	09-2003	Ariga, Kenichi	455/565
	D	US-6,414,635 B1	07-2002	Stewart et al.	342/457
	E	US-2002/0016742	02-2002	Razumov, Sergey N.	705/26
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2002042189 A	02-2002	Japan	MANABE, SHUNICHI	G07B 15/00
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.